

PB1200

probe card analyzer



overview

The Probilt bench-top line of analyzers is a totally new concept in probe card test and repair. These systems are designed for stand alone use and as a companion tool for the higher end probe card analyzers. The probe card is tested and repaired in a "tips up" position which eliminates the time to flip from test to repair position. They may be used to perform a complete test or import test data from a larger analyzer. Repair and retest of individual probes is easily performed. Specialized software routines quickly identify the failing probe and place the microscope crosshair at the correct position for quick and easy alignment. After repair, each individual probe may be retested for alignment and planarity.

The PB1200 is an automated probe card repair system. It has the capability to fully test alignment, planarity and (optionally) gram force, but its main purpose is in card repair. Test data may also be imported from a PB3600, PB6500 or other manufacturers probe card analyzers. The repair process consists of selecting a failing probe, which moves it under the binocular microscope and positions a crosshair over the correct position for that probe. Thus the probe is not only easily identified, the operator has a true reference (the crosshair) for the correct alignment position. The repair process time is cut to 1/2 or 1/3 that of standard analyzers or alignment stations.

features

- Fast, simple probe card repair
 - Crosshair shows correct probe position
 - Tips up configuration for easy repair
 - Excellent ergonomics
 - Fast retest without flip
 - Leica MZ80 binocular microscope
- Accurate, repeatable stage
 - Closed loop with 0.1u encoders
 - 6" x 6" stage movement
 - Up to 3" x 3" arrays
 - 100 lb Force Z stage, 2.0" stroke
- Simple, economical card holders
 - No motherboards
 - Fast change card holders/probe cards
 - Up to 15" diameter probe cards
- Powerful Probilt™ software
 - Same software as PB3600/6500
 - Network with PB3600/6500
- Works with all probe card technologies
 - Excellent for tight pitch shelf cards

tests performed

- Alignment
- Planarity
- Gram Force (optional)

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card holders

- Lightweight for easy installation
- Precision tooled for accurate wafer probe correlation
- Compatible with up to 15" diameter probe cards



available option

- Gram Force – Allows accurate measurement of gram force for each pin at the specified overdrive.



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